

Title (en)  
**METHOD AND APPARATUS FOR PHOTOINDUCTIVE IMAGING**

Publication  
**EP 0479918 A4 19930929 (EN)**

Application  
**EP 90911486 A 19900720**

Priority  
**US 51011290 A 19900417**

Abstract (en)  
[origin: WO9116638A1] A system for photoinductive imaging for flaw detection of materials and for calibrating eddy-current probes includes positioning an eddy-current probe (14) adjacent to a specimen (12) to be analyzed or to be used as a calibration fixture. A source of thermal energy (20) is modulated and focused to a localized area on the specimen. Thermal energy is then scanned across at least a portion of the detection area of the eddy-probe (14). The resulting signal from the eddy-current probe (14) is recorded and can depict either thermal-influenced components of the specimen (12) or the response pattern of the eddy-current probe (14). The record can therefore be used to image flaws or physical holes or shapes of the specimen or calibrate the eddy-current probe (14).

IPC 1-7  
**G01R 35/00**

IPC 8 full level  
**G01N 25/72** (2006.01); **G01N 27/90** (2006.01); **G01R 35/00** (2006.01); **H04N 5/33** (2006.01)

CPC (source: EP)  
**B82Y 15/00** (2013.01); **G01N 25/72** (2013.01); **G01N 27/902** (2013.01); **G01R 35/00** (2013.01)

Citation (search report)

- No further relevant documents disclosed
- See references of WO 9116638A1

Designated contracting state (EPC)  
**DE GB**

DOCDB simple family (publication)  
**WO 9116638 A1 19911031**; EP 0479918 A1 19920415; EP 0479918 A4 19930929; JP H05500416 A 19930128

DOCDB simple family (application)  
**US 9004120 W 19900720**; EP 90911486 A 19900720; JP 51109090 A 19900720